### April 2nd - Time

**Monday-Track 1 - Silicon Modes - REGENCY MAIN**

<table>
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<tr>
<th>Time</th>
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| 8:10-10:00am  | 1-1 Fundamental FEOL Reliability: Defect Generation in Gate Dielectrics to Induce Dielectric Breakdown and Device Degradation  
Ken Oheda - Towa/Jazz Panasonic Semiconductor  
Bill Bouch - Genaro                                                             |
| 10:00-10:30am | Lunch                                                                                       |
| 10:30-noon    | 1-2 Interconnect Reliability Fundamentals  
Qudd Toker (IMEC)  
Michael Zaslavsky and Tim Turner - The Reliability Simulation Group         |
| noon-1:30pm   | Lunch                                                                                       |
| 1:30-3:00pm   | 2-1 Compound Semiconductor Reliability 101  
Kenji Okada - TowerJazz Panasonic Semiconductor  
Bill Roesch - Qorvo                                                               |
| 3:00-3:30pm   | 2-2 VLSI Design Methodology and Design Verification for Reliability  
Zsolt Tokei (IMEC)  
Michael Zaslavsky and Tim Turner - The Reliability Simulation Group         |
| 3:30-5:00pm   | 3-1 Interconnect Reliability Fundamentals  
Qudd Toker (IMEC)  
Michael Zaslavsky and Tim Turner - The Reliability Simulation Group         |
| 8:30-10:00am  | Lunch                                                                                       |
| 10:00-11:30am | 2-3 NAND Flash Memory Reliability  
Cathy Christensen - Global Foundries  
Hanmant Belgal and Ivan Kalastirsky - Intel                                    |
| 11:30am-12:30pm| Lunch                                                                                       |
| 12:30-2:00pm  | 3-2 Interconnect Reliability Fundamentals  
Qudd Toker (IMEC)  
Michael Zaslavsky and Tim Turner - The Reliability Simulation Group         |
| 2:00-2:30pm   | Lunch                                                                                       |
| 2:30-5:00pm   | 3-3 NAND Flash Memory Reliability  
Cathy Christensen - Global Foundries  
Hanmant Belgal and Ivan Kalastirsky - Intel                                    |

### April 3rd - Time

**Monday-Track 1 - Advanced Si&Pkg - REGENCY MAIN**

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| 8:00-9:30am   | 4-1 Recent Advances in Negative Bias Temperature Instability (NBTI) in HKMG p-MOSFETs and 2. The Emerging Challenge of Self-heating In Modern FINFET, ETSOI, and Gate All-Around III-V Transistors: A Transistor to Tablet Perspective  
Souvik Mahapatra (IIT, Bombay)  
Muhammad Ashraf Alam (Purdue)    |
| 10:00-10:30am | Lunch                                                                                       |
| 10:30-noon    | 5-1 he automotive transformation – cost, time-to-market, reliability and security driven design optimization from application down to semiconductor technology  
Peter Memos - ON semiconductor  
Rob Kwasnick - Intel             |
| noon-1:30pm   | Lunch                                                                                       |
| 1:30-3:00pm   | 5-2 Advanced MOL and BEOL Reliability  
Shou Chung Lee - TSMC  
Carl Gozd - NVIDIA  
Hans Postoli - IBM  
Gerry Gan - IBM     |
| 3:00-3:30pm   | 6-1 Advanced Packaging and 3D Reliability  
C. Ramu Kodandaraman - IBM  
Sub Knoedl - Automotive Electronics Council & NXP  
Daniel C. Worledge - IBM  
Arijit Biswas - Intel                  |
| 3:30-5:00pm   | 6-2 Introduction to Automotive Functional Safety - History, Trends, and Relation to Reliability  
Arijit Biswas - Intel                  |
| 9:30-10:00am  | Break                                                                                       |
| 10:00-11:30am | Break                                                                                       |
| 11:30am-12:30pm| Lunch                                                                                       |
| 12:30-2:00pm  | 6-3 Phase Change Memory: From Basic Technology to System Aspects and New Applications  
Arijit Biswas - Intel                  |
| 2:00-2:30pm   | Break                                                                                       |
| 2:30-5:00pm   | 6-4 Juggling Knowledge Based and Standards Based Qualification  
Arijit Biswas - Intel                  |
| 3:30-5:00pm   | 6-5 Considerations for In-field Reconfiguration, Self-healing, Detection & Recovery Techniques  
Arijit Biswas - Intel                  |